

**Notice of References Cited**

Application/Control No.

10/023,700

Applicant(s)/Patent Under

Reexamination

HATCH ET AL.

Examiner

Raymond S Dean

Art Unit

2684

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0060240 A1	03-2003	Graham et al.	455/566
	B	US-6,169,897 B1	01-2001	Kariya, Kazuo	455/456.3
	C	US-5,797,098	08-1998	Schroeder et al.	455/464
	D	US-2002/0151334 A1	10-2002	Sharma, Ochintya	455/566
	E	US-6,650,892 B1	11-2003	Thiriet, Fabien	455/419
	F	US-2003/0078033 A1	04-2003	Sauer et al.	455/412
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.